



FORM PTO 1449 (modified)  U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE  LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary)  Date Submitted to PTO: [DATE]				ATTY DOCKET NO. <b>03500.017320.</b>		APPLICATION NO. <b>10/516,545</b>	
				APPLICANTS <b>TAKESHI ICHIKAWA ET AL.</b>			
				FILING DATE <b>DECEMBER 2, 2004</b>		GROUP <b>2879</b>	

U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
R		2002-057045	05/16/02	Tsukamoto	313	309	

FOREIGN PATENT DOCUMENTS							
	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT	
R	EPA	1056110	11/29/00	EPO	H01J	1/30	
R		03/046255	06/05/03	WIPO	C23C	16/56	
R		99/028939	06/10/99	WIPO	H01J	1/30	

OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)		

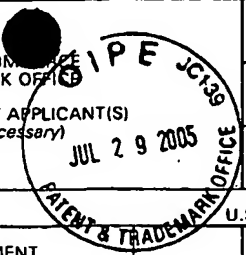
  

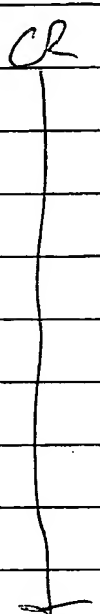
EXAMINER	DATE CONSIDERED <u>1/21/07</u>
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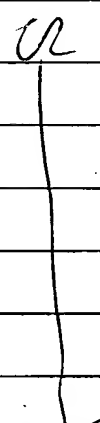
\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

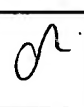
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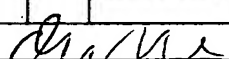
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U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
	4,663,559	5/87	Christensen	313	336		
	5,939,823	8/99	Kiyomiya et al.	313	495		
	5,989,404	11/99	Kiyomiya et al.	205	96		
	6,288,494	9/01	Tsukamoto et al.	315	169.1		
	6,583,582	6/03	Ichikawa	315	169.3		
	6,583,553	6/03	Sasaguri	313	495		
	6,650,061	11/03	Urayama et al.	315	169.3		
	6,683,408	1/04	Ichikawa	313	495		
	2004/0251812 A1	12/04	Fujiwara et al.	313	495		
	6,861,790	3/05	Iwasa et al.	313	346		

FOREIGN PATENT DOCUMENTS							
DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT		
	8-96703	4/96	Japan				Abstract
	2001-6523	1/01	Japan				Abstract
	2001-101966	4/01	Japan				Abstract
	4-131846	5/92	Japan				Abstract
	8-96704	4/96	Japan				Abstract
	8-264109	10/96	Japan				Abstract
	2001-202870	7/01	Japan				Abstract



OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)	
	<b>Forest, R.D., et al., A Study of Electron Field Emission as a function of film thickness from amorphous Carbon Films, Applied Physics Letters, Vol. 73, No. 25, pp 3784-3786 (1998)</b>

EXAMINER 	DATE CONSIDERED <u>1/21/07</u>
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10/516545

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APPLICANT <b>TAKESHI ICHIKAWA ET AL.</b>		FILING DATE <b>FILED HEREWITH</b>		GROUP <b>NYA</b>			
U.S. PATENT DOCUMENTS							
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		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)							
		S.P. Lau et al., "Field Emission from Metal-Containing Amorphous Carbon Composite Films", <u>Diamond and Related Materials</u> , Vol. 10 (2001); pp. 1727-1731.					
		Richard G. Forbes, "Low-Macroscopic-Field Electron Emission From Carbon Films and Other Electrically Nanostructured Heterogeneous Materials: Hypotheses About Emission Mechanism", <u>Solid State Electronics</u> , Vol. 45 (2001); pp. 779-808.					
EXAMINER		DATE CONSIDERED <u>1/21/07</u>					

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